

**Search Notes**

Application/Control No.

10/749,045

Examiner

Mathieu D. Vargot

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

1732

**SEARCHED**

Class	Subclass	Date	Examiner
264	1.1, 1.24, 1.31, 2.5		
425	808,		
	810	9/29/06	ADV

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR